

Notice of References Cited

Application/Control No.

10/559,527

Applicant(s)/Patent Under
Reexamination
SHINKAI ET AL.

Examiner

ANEETA PATANKAR

Art Unit

4134

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0097645	07-2002	Mikawa, Takuma	369/47.1
*	B	US-2002/0154898	10-2002	Hisatomi et al.	386/95
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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	P					
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NON-PATENT DOCUMENTS

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